

**Search Notes**

Application/Control No.

10/769,684

Examiner

Leon J. Harper

Applicant(s)/Patent under  
Reexamination

BONILLA ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	104.1,1, 100,10	9/7/2006	LJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR